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**Supporting Information** 

Tunable crystallographic grain orientation and Raman fingerprint of polycrystalline SnO thin films

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## S1. XRD patterns of bare SnO films of different thickness

The films with the thickness below 60 nm exhibit a (001) peak located at  $\sim 18.4^{\circ}$  and a (002) peak located at  $\sim 37.3^{\circ}$ , respectively. With increasing the thickness of SnO film, a (101) peak located at  $\sim 30.0^{\circ}$  is present, while the (001) and (002) peaks are suppressed. Especially, the (101) peak is dominant and the (00*l*)-orientated peaks are weak when the SnO thickness is above 100 nm.

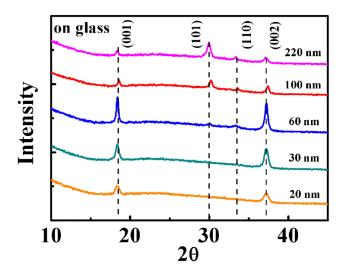


Figure S1. XRD patterns of bare SnO films of different thickness.

## S2. XRD patterns of thick SnO films with Al<sub>2</sub>O<sub>3</sub> capping layer of different thickness

With increasing  $t_{Al_2O_3}$ , the (001) and (002) peaks are suppressed and the (101) peak is enhanced.

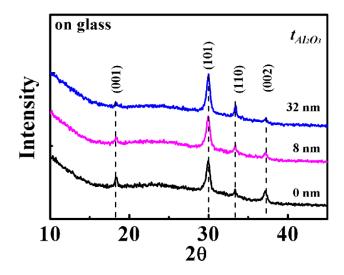


Figure S2. XRD patterns of 220 nm-thick SnO films with  $Al_2O_3$  capping layer of different thickness.

## S3. Raman spectra of the SnO films of different thickness

The Raman spectrum of the thin SnO films (20 nm and 30 nm) shows only one peak located at 210 cm<sup>-1</sup>, in according to the (001) preferred orientation measured by the XRD. With the increasing film thickness, the 110 cm<sup>-1</sup> peak intensity increases gradually and is comparable to that of the 210 cm<sup>-1</sup> peak when the SnO thickness is above 100 nm, coupling with the enhancement of the (101) grains.

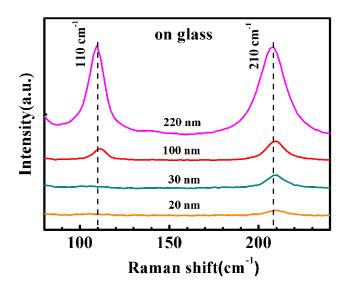


Figure S3. Raman spectra of bare SnO films of different thickness.